

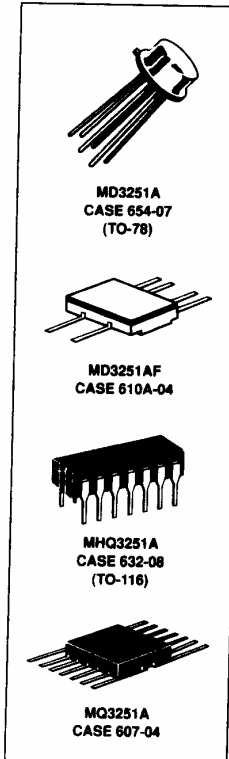
**MD3251AHX, HXV (DUAL)**  
**MD3251AFHXV (DUAL)**  
**MHQ3251AHX, HXV (QUAD)**  
**MQ3251AHXV (QUAD)**

**CRYSTALONCS**  
**2805 Veterans Highway**  
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**Ronkonkoma, N.Y. 11779**

**PNP Silicon Dual/Quad**  
**Small-Signal Transistors**

... designed for general-purpose amplifier applications. Matched devices for DC current gain, base-emitter saturation voltage, and tracking over military temperature range.

MAXIMUM RATINGS				
Rating	Symbol	Value		Unit
Collector-Emitter Voltage	V <sub>CEO</sub>	60		Vdc
Collector-Base Voltage	V <sub>CBO</sub>	60		Vdc
Emitter-Base Voltage	V <sub>EBO</sub>	5.0		Vdc
Collector Current — Continuous	I <sub>C</sub>	200		mAdc
		One Die	All Die Equal Power	
Total Device Dissipation @ T <sub>A</sub> = 25 C	P <sub>T</sub>			Watts
MD3251A		0.575	0.625	
MD3251AF		0.35	0.4	
MHQ3251A		0.5	1.5	
MQ3251A		0.4	0.6	
Derate above 25 C				mW/°C
MD3251A		3.29	3.57	
MD3251AF		1.0	2.28	
MHQ3251A		2.86	8.58	
MQ3251A		2.28	3.42	
@ T <sub>C</sub> = 25 C				Watts
MD3251A		1.8	2.5	
MD3251AF		1.0	2.0	
MHQ3251A		1.0	3.5	
MQ3251A		0.9	3.6	
Derate above 25°C				mW/°C
MD3251A		10.3	14.3	
MD3251AF		5.71	11.4	
MHQ3251A		5.71	20	
MQ3251A		5.13	20.5	
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-65 to 200		°C



ELECTRICAL CHARACTERISTICS (T <sub>A</sub> = 25°C unless otherwise noted.)				
Characteristic	Symbol	Min	Max	Unit
<b>OFF CHARACTERISTICS</b>				
Collector-Emitter Breakdown Voltage <sup>(1)</sup> (I <sub>C</sub> = 10 mA, I <sub>B</sub> = 0)	V <sub>(BR)CEO</sub>	60	—	Vdc
Collector-Emitter Breakdown Voltage (I <sub>C</sub> = 10 μA, I <sub>E</sub> = 0)	V <sub>(BR)CBO</sub>	60	—	Vdc
Emitter-Base Breakdown Voltage (I <sub>E</sub> = 10 μA, I <sub>C</sub> = 0)	V <sub>(BR)EBO</sub>	5.0	—	Vdc
Collector Cutoff Current (V <sub>CB</sub> = 40 Vdc, I <sub>E</sub> = 0) (V <sub>CB</sub> = 40 Vdc, I <sub>E</sub> = 0, T <sub>A</sub> = 150°C)	I <sub>CBO</sub>	— —	20 10	nAdc μAdc
Collector Cutoff Current (V <sub>CE</sub> = 40 Vdc, V <sub>EB(off)</sub> = 3.0 Vdc) (V <sub>CE</sub> = 40 Vdc, V <sub>EB(off)</sub> = 3.0 Vdc, T <sub>A</sub> = 150°C)	I <sub>CEX</sub>	— —	20 20	nAdc μAdc
Emitter Cutoff Current (V <sub>CE</sub> = 40 Vdc, V <sub>EB(off)</sub> = 3.0 Vdc)	I <sub>BEX</sub>	—	50	nAdc
<b>ON CHARACTERISTICS</b>				
DC Current Gain <sup>(1)</sup> (I <sub>C</sub> = 0.1 mA, V <sub>CE</sub> = 1.0 Vdc) (I <sub>C</sub> = 1.0 mA, V <sub>CE</sub> = 1.0 Vdc) (I <sub>C</sub> = 10 mA, V <sub>CE</sub> = 1.0 Vdc) <sup>(1)</sup> (I <sub>C</sub> = 50 mA, V <sub>CE</sub> = 1.0 Vdc) <sup>(1)</sup> (I <sub>C</sub> = 1.0 mA, V <sub>CE</sub> = 1.0 Vdc, T <sub>A</sub> = -55°C)	h <sub>FE</sub>	80 90 100 30 40	— — 300 — —	—
Collector-Emitter Saturation Voltage (I <sub>C</sub> = 10 mA, I <sub>B</sub> = 1.0 mA) (I <sub>C</sub> = 50 mA, I <sub>B</sub> = 5.0 mA) <sup>(1)</sup>	V <sub>CE(sat)</sub>	— —	0.25 0.5	Vdc
Base-Emitter Saturation Voltage (I <sub>C</sub> = 10 mA, I <sub>B</sub> = 1.0 mA) (I <sub>C</sub> = 50 mA, I <sub>B</sub> = 5.0 mA) <sup>(1)</sup>	V <sub>BE(sat)</sub>	0.6 —	0.9 1.2	Vdc
<b>SMALL-SIGNAL CHARACTERISTICS</b>				
Output Capacitance (V <sub>CB</sub> = 10 Vdc, I <sub>E</sub> = 0, f = 100 kHz to 1.0 MHz)	C <sub>obo</sub>	—	6.0	pF
Input Capacitance (V <sub>BE</sub> = 1.0 Vdc, I <sub>C</sub> = 0, f = 100 kHz to 1.0 MHz)	C <sub>ibo</sub>	—	8.0	pF
Current Gain (I <sub>C</sub> = 1.0 mA, V <sub>CE</sub> = 10 Vdc, f = 1.0 kHz)	h <sub>fe</sub>	100	400	—
Small-Signal Current Transfer Ratio, Magnitude (I <sub>C</sub> = 10 mA, V <sub>CE</sub> = 20 Vdc, f = 100 MHz)	h <sub>fe</sub>	3.0	9.0	—
<b>SWITCHING CHARACTERISTICS</b>				
Delay Time	t <sub>d</sub>	—	35	ns
Rise Time	t <sub>r</sub>	—	35	ns
Storage Time	t <sub>s</sub>	—	200	ns
Fall Time	t <sub>f</sub>	—	50	ns

(1) Pulsed. Pulse Width ≤ 300 μs. Duty Cycle ≤ 2.0%

(continued)

ELECTRICAL CHARACTERISTICS — continued (T <sub>A</sub> = 25°C unless otherwise noted.)				
Characteristic	Symbol	Min	Max	Unit
<b>MATCHING CHARACTERISTICS (Duals Only)</b>				
DC Current Gain Ratio (I <sub>C</sub> = 0.1 mA, V <sub>CE</sub> = 5.0 Vdc) (I <sub>C</sub> = 1.0 mA, V <sub>CE</sub> = 5.0 Vdc)	h <sub>FE1</sub> /h <sub>FE2</sub> <sup>*</sup>	0.9 0.9	1.0 1.0	—
Base-Emitter Voltage Differential (I <sub>C</sub> = 0.01 mA, V <sub>CE</sub> = 5.0 Vdc) (I <sub>C</sub> = 0.1 mA, V <sub>CE</sub> = 5.0 Vdc) (I <sub>C</sub> = 10 mA, V <sub>CE</sub> = 5.0 Vdc)	(V <sub>BE1</sub> - V <sub>BE2</sub> )	— — —	5.0 3.0 5.0	mVdc
Base-Emitter Voltage Differential Change Due to Temperature (I <sub>C</sub> = 0.1 mA, V <sub>CE</sub> = 5.0 Vdc, T <sub>A</sub> = -55 to +25°C) (I <sub>C</sub> = 0.1 mA, V <sub>CE</sub> = 5.0 Vdc, T <sub>A</sub> = +25 to +125°C)	Δ(V <sub>BE1</sub> - V <sub>BE2</sub> )	— —	0.8 1.0	mVdc

ASSURANCE TESTING (Pre/Post Burn-In)				
Characteristics Tested	Symbol	Initial and End Point Limits		Unit
		Min	Max	
Collector Cutoff Current (V <sub>CB</sub> = 40 Vdc)	I <sub>CBO</sub>	—	20	nAdc
DC Current Gain <sup>(1)</sup> (I <sub>C</sub> = 10 mA, V <sub>CE</sub> = 1.0 Vdc)	h <sub>FE</sub>	100	300	—

Delta from Pre-Burn-In Measured Values				
		Min	Max	
Delta Collector Cutoff Current	ΔI <sub>CBO</sub>	—	±100 or ±5.0 whichever is greater	% of Initial Value nAdc
Delta DC Current Gain <sup>(1)</sup>	Δh <sub>FE</sub>	—	±25	% of Initial Value

\* The lowest base current is taken as h<sub>FE1</sub> for this test.